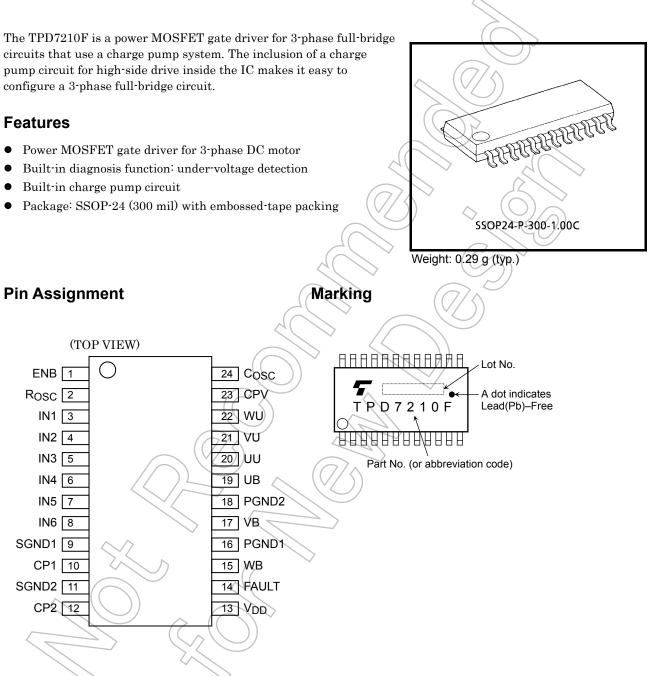
TOSHIBA Intelligent Power Device Silicon Monolithic Power MOS Integrated Circuit

TPD7210F



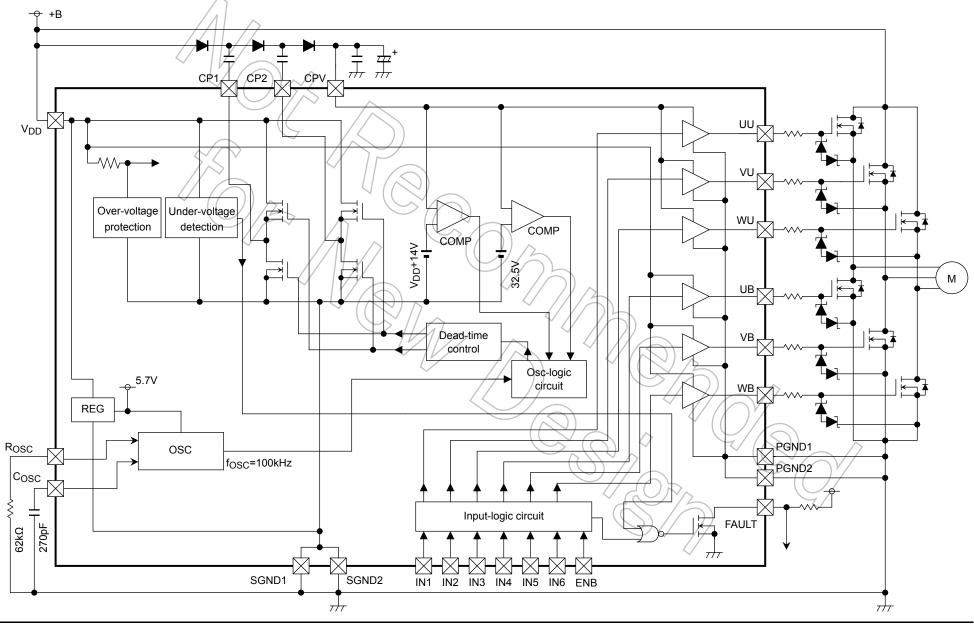


This product has a MOS structure and is sensitive to electrostatic discharge.

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TPD7210F

Block Diagram / Application Circuit



Pin Description

Pin No.	Symbol	Pin Description
1	ENB	Inhibit pin (high active): By driving this pin low, all outputs can be turned off regardless of input signals. Built-in pull-down resistor (100 k Ω typ.).
2	R _{OSC}	This pin sets the oscillation frequency for the charge pump drive. Connect a 62 k Ω (typ.) resistor.
3	IN1	Input pin: it controls the power MOSFET connected to UU. Built-in pull-down resistor (100 k Ω typ.).
4	IN2	Input pin: it controls the power MOSFET connected to VU. Built-in pull-down resistor (100 k Ω typ.).
5	IN3	Input pin: it controls the power MOSFET connected to WU. Built-in pull-down resistor (100 k Ω typ.).
6	IN4	Input pin: it controls the power MOSFET connected to UB. Built-in pull-down resistor (100 k Ω typ.).
7	IN5	Input pin: it controls the power MOSFET connected to VB. Built-in pull-down resistor (100 k Ω typ.).
8	IN6	Input pin: it controls the power MOSFET connected to WB. Built-in pull-down resistor (100 k Ω typ.).
9	SGND1	Signal block GND pin: shared internally with pin 11.
10	CP1	Capacitor pin for charge pump.
11	SGND2	Signal block GND pin: shared internally with pin 9.
12	CP2	Capacitor pin for charge pump.
13	V _{DD}	Power supply pin: when under-voltage (5.5 V typ.) is detected, FAULT output goes high. On this occasion, all outputs are switching normally, and charge pump circuit does not come to a stop.
14	FAULT	Diagnosis output pin: when under-voltage (5.5 V typ.) is detected, FAULT output goes high. High-side/low-side arm shorting mode, FAULT output goes high and all outputs are shut down. Circuit configuration is N-ch open drain.
15	WB	Drives the power MOSEET connected to the low side of the W phase.
16	PGND1	Power block GND pin: shared internally with pin 18.
17	VB	Drives the power MOSFET connected to the low side of the V phase.
18	PGND2	Power block GND pin: shared internally with pin 16.
19	UB	Drives the power MOSFET connected to the low side of the U phase.
20	UU	Drives the power MOSFET connected to the high side of the U phase.
21	VU	Drives the power MOSFET connected to the high side of the V phase.
22	WU	Drives the power MOSFET connected to the high side of the W phase.
23	CPV	Final stage capacitor pin for the charge pump.
24	Cosc	This pin sets the oscillation frequency for the charge pump drive. Connect a 270pF (typ.) capacitor.

Truth Table (All outputs go to low for input in high-side/low-side arm shorting mode)

Mode			Inp	out					Ou	tput			
No.	IN1 (UU)	IN2 (VU)	IN3 (WU)	IN4 (UB)	IN5 (VB)	IN6 (WB)	OUT UU	OUT VU	OUT WU	OUT UB	OUT VB	OUT WB	Remarks
01	L	L	L	L	L	L	L	L	L	L	L	L	
02	Н	L	L	L	L	L	Н	L	L	L	L	L	
03	L	Н	L	L	L	L	L	Н	L	L	L	L	
04	L	L	Н	L	L	L	L	L	Н	L	L	L	
05	L	L	L	Н	L	L	L	L	L	Н	L	4	$\langle \langle \langle \rangle \rangle \rangle$
06	L	L	L	L	Н	L	L	L	L	L	Н	L	
07	L	L	L	L	L	Н	L	L	L	L	L	н	
08	Н	L	L	Н	L	L	L	L	L	L	L	(L	High-side/low-side arm shorting mode *
09	Н	L	L	L	Н	L	н	L	L	L	н<	کر	120° square wave conducting normal mode
10	Н	L	L	L	L	Н	н	L	L	L	(\mathbf{F})	×۲	120° square wave conducting normal mode
11	L	Н	L	Н	L	L	L	Н	L	Н	X)y	120° square wave conducting normal mode
12	L	Н	L	L	Н	L	L	L	L	F	14	L	High-side/low-side arm shorting mode *
13	L	Н	L	L	L	Н	L	Н	L	1		Н	120° square wave conducting normal mode
14	L	L	Н	Н	L	L	L	L	É.	۲ ۲	\geq_{L}	L	120° square wave conducting normal mode
15	L	L	Н	L	Н	L	L	L (Æ	P	Н	L	120° square wave conducting normal mode
16	L	L	Н	L	L	Н	L	4	Ļ	L	L	É	High-side/low-side arm shorting mode *
17	Н	Н	L	L	L	L	Н	H	2	L	/L	L	
18	L	Н	Н	L	L	L	4	H	Ŧ	L	L	Y))
19	Н	L	Н	L	L	L	Я	Ľ)	Н	L	L	L	
20	L	L	L	н	Н	4	4	L	L	н	Ч	L	
21	L	L	L	L	н	H	I)	L	L	4	H	н	
22	L	L	L	Н	-60	7.A	L	L	L	H	L L	́н	
23	Н	Н	L	Ŧ	7	\Box	L	L	4		γ	L	High-side/low-side arm shorting mode *
24	Н	Н	Ľ	_ L/)	<u>_</u>	7 ^L	L	Ĺ		(\mathbf{p})	L	L	High-side/low-side arm shorting mode *
25	Н	Н	L	X	L	Н	H_	H	4	ì	L	Н	
26	L	Н	Н	Н	Y.	L	\mathcal{A}	F	Ì	Н	L	L	
27	L	Æ	́н	L	Н	L	L	7	L	L	L	L	High-side/low-side arm shorting mode *
28	L	H	Æ	ノ	L	Н	γL	L	Ĺ	L	L	L	High-side/low-side arm shorting mode *
29	Н	(F	Н	L	Ľ	L	L	L	L	L	L	High-side/low-side arm shorting mode *
30 <	H	K	H	L	н	$\overline{+}$	H	L	Н	L	Н	L	

* High-side/low-side arm shorting mode is disabled by the internal logic. FAULT output goes high (open-drain, high-impedance)

*: By driving ENB pin low, all outputs can be turned off regardless of input signals. By driving ENB pin high, all outputs are switching normally.

Mada			Inp	out			Output						
Mode No.	IN1 (UU)	IN2 (VU)	IN3 (WU)	IN4 (UB)	IN5 (VB)	IN6 (WB)	OUT UU	OUT VU	OUT WU	OUT UB	OUT VB	OUT WB	Remarks
31	Н	L	Н	L	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *
32	Н	L	L	Н	Н	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *
33	Н	L	L	L	Н	Н	Н	L	L	L	н	Н	
34	Н	L	L	Н	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *
35	L	Н	L	Н	Н	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *
36	L	Н	L	L	Н	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *
37	L	Н	L	Н	L	Н	L	Н	L	Н	L	н	
38	L	L	Н	Н	Н	L	L	L	н	Н	н	L (
39	L	L	Н	L	Н	Н	L	L	L	L	L	L.	High-side/low-side arm shorting mode *
40	L	L	Н	Н	L	Н	L	L	L	L	L		High-side/low-side arm shorting mode *
41	Н	Н	Н	L	L	L	Н	н	н	L	L	L	
42	L	L	L	Н	Н	Н	L	L	L	Н	([H]/	(Ĥ	
43	Н	Н	L	Н	Н	L	L	L	L	L		2	High-side/low-side atm shorting mode *
44	Н	Н	L	L	Н	Н	L	L	L	10	L	L	High-side/low-side arm shorting mode *
45	Н	Н	L	Н	L	Н	L	L	<u>ل</u> ر(2	SL.	L	High-side/low-side arm shorting mode *
46	L	Н	Н	Н	Н	L	L	L	-L	L	L	L	High-side/low-side arm shorting mode *
47	L	Н	Н	L	Н	Н	L	4	L	Y	L	L	High-side/low-side arm shorting mode *
48	L	Н	Н	Н	L	Н	L	4	Ł	L	K	T	High-side/low-side arm shorting mode *
49	Н	L	Н	Н	Н	L	Y	-L	7	L	$\langle \langle \rangle$	L	High-side/low-side arm shorting mode *
50	Н	L	Н	L	Н	Н		L)	L	L	L	Ŀ	High-side/low-side arm shorting mode *
51	Н	L	Н	Н	L	H			L	L	L	L	High-side/low-side arm shorting mode *
52	Н	Н	Н	Н	L	(L(L)	L	L	Ļ	4	L	High-side/low-side arm shorting mode *
53	Н	Н	Н	L	Ŧ	4	Y	L	L	Ĺ	Ŧ	> L	High-side/low-side arm shorting mode *
54	Н	Н	н	ť	- (L)	(н)	L	L	L	L		L	High-side/low-side arm shorting mode *
55	Н	L	L//	H) н	Ŧ	L	L		74	L	L	High-side/low-side arm shorting mode *
56	L	Н	\sim	H/	H	∕н	L	F		Ľ	L	L	High-side/low-side arm shorting mode *
57	L	L	Н	H	Ŧ	Н	Ę	L	L	, L	L	L	High-side/low-side arm shorting mode *
58	Н	н	H	Н	Н	L	L	F	L	L	L	L	High-side/low-side arm shorting mode *
59	Н	H	F	K	Н	Н	L	L	∑L	L	L	L	High-side/low-side arm shorting mode *
60	Н	Ŧ	H	Ч	L	H	Ĺ	L	L	L	L	L	High-side/low-side arm shorting mode *
61 🤇	Н	((H)L)	Н	Н	H	A	L	L	L	L	L	High-side/low-side arm shorting mode *
62	Z	Ŧ	1	H	> H (H) L	L	L	L	L	L	High-side/low-side arm shorting mode *
63	H		Н	H	Ŕ	F	儿	L	L	L	L	L	High-side/low-side arm shorting mode *
64	H	Н	Н	Н	Æ	Ŧ	L	L	L	L	L	L	High-side/low-side arm shorting mode *

*: High-side/low-side arm shorting mode is disabled by the internal logic. FAULT output goes high (open-drain, high-impedance)

*: By driving ENB pin low, all outputs can be turned off regardless of input signals. By driving ENB pin high, all outputs are switching normally.

Absolute Maximum Ratings (T_a = 25°C)

Characteristic	Symbol	Rating	Unit	Remarks			
Power supply voltage	V _{DD(1)}	-0.5 to 30	V				
Power supply voltage	V _{DD(2)}	45	V	Pulse width \leq 200ms			
Output current	ISOURCE	1	Α	Pulse width $\leq 10 \mu s$			
Ouput current	ISINK	1	~				
Input voltage	V _{IN} , V _{ENB}	-0.5 to 7.0	V				
FAULT pin voltage	VFAULT	30	V				
PGND pin negative voltage	P _{GND} (-)	-0.5	v	Negative voltage that can be applied to PGND pin (reference to SGND pin)			
Output pin negative voltage	V _{OUT(-)}	-0.5	X	Negative voltage that can be applied to UU, VU,WU,UB,VB and WB pins (Reference to SGND pin)			
FAULT pin current	IFAULT	5	mA				
Power dissipation	PD	0.8 1.2 (Note2)	Ŵ	*			
Operating temperature	T _{opr}	-40 to 125	°C				
Junction temperature	Тј	150	°C				
Storage temperature	T _{stg}	-40 to 150	°C				

Note1 : Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Resistance

Characteristic	Symbol	Rating	Unit
Junction to ambient thermal resistance	Pit (T)	156.3	°C/W
	Rth (j-a)	104.2 (Note2)	0770

Note2: When the device is mounted on a 60 mm × 60 mm × 1.6 mm glass epoxy PCB

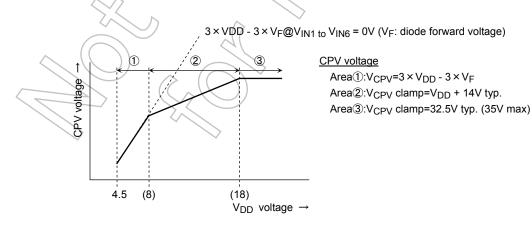
Electrical Characteristics (Unless otherwise specified, T_a = -40 to 125°C, CP1, 2 = 0.1μ F, R_{OSC} = $62k\Omega$, C_{OSC} = 270pF)

Characteristic	Symbol	Test Circuit	Condition	Min	Тур.	Max	Unit	Remarks			
Operating supply voltage (Note3)	V _{DD(opr)}	-	-	4.5	13.5	18	V				
	I _{DD(1)}	-	V _{DD} = 13.5 V	-	-	7		Oscillation circuit stops			
Supply current	I _{DD(2)}	-	V _{DD} = 13.5 V, V _{IN1} to V _{IN6} = 0 V, CP1,2 = 0.1μF	-	-	9	mA	When oscillation circuit is operating f = 100 kHz, mean current			
Input voltage	V _{IH}		V _{DD} = 7 to 18 V,	3.5	-			IN1 to IN6 and ENB High-level input voltage			
input voltage	VIL		I _O = 0 A	-	- ((1.5	v	IIN1 to IN6 and ENB low-level input voltage			
Input current	IIH	_	V _{DD} = 7 to 18V, V _{IN} = 5 V	-		200	μA	IN1 to IN6, ENB input current			
input current	Ι _{ΙL}		V _{DD} = 7 to 18 V, V _{IN} = 0 V	- 10		10	μA	(per one input)			
01			V _{DD} = 7 V, V _{IN1} to V _{IN6} = 0 V	V _{DD} +10.9	V _{DD} +11.9			$V_{CPV} \approx 3 \times (V_{DD} - V_F)$ V_{CPV} denotes CPV pin voltage. (reference to SGND pin)			
Charge pump voltage (Note4)(Note5)	V _{CPV}	-	V _{DD} = 13.5 V, V _{IN1} to V _{IN6} = 0 V	V _{DD} +12	V _{DD} +14	V _{DD} +16	Z.	V _{CPV} denotes CPV pin voltage.			
			V _{DD} = 18 V, V _{IN1} to V _{IN6} ≓ 0 V	V _{DD} +12	V _{DD} +14	V _{DD} +16	v	(reference to SGND pin)			
	V _{OH(H1)}		V _{DD} = 7V, V _{IN} = 5V, I _O = -10mA	_	V _{DD} + 9.9)) -					
High-side high-level output voltage	V _{OH(H2)}	_	$V_{DD} = 13.5 V,$ $V_{IN} = 5 V,$ $I_{O} = -10 mA$	-	V _{DD} + 12	I	-	UU, VU and WU pin voltage (reference to SGND pin) *Measuring single pulse			
	V _{OH(H3)}		V _{DD} = 18 V, V _{IN} = 5 V, I _O = -10 mA		V _{DD} + 12	-					
High-side high-level output voltage drop	VDROP		V _{IN} = 5 V, H _O = -10 mA, V _{DROP} = V _{CPV} - V _Q H	\bigcirc	2	3	v				
High-side low-level output voltage	Vol(H)	-	V _{DD} = 7 to 18 V, V _{IN} = 0 V, I _O = 0 A		-	0.1					
Low-side high-level output voltage	V _{OH(L)}	-	V _{DD} = 7 to 18V, V _{IN} = 5V, I _O = -10mA	V _{DD} - 0.1	V _{DD}	_		UB, VB and WB pin voltage			
Low-side low-level output voltage	V _{OL(L)}	(($V_{DD} = 7 \text{ to } 18 \text{ V},$ $V_{IN} = 0 \text{ V},$ $V_{Q} = 0 \text{ A}$	-	-	0.1		(reference to SGND pin)			
	R _{SOURCE}		V _{DD} = 13.5 V, V _{IN} = 5 V, I _O = -0.5 A	-	7	10	0	UU, VU, WU, UB, VB and			
Output ON resistance	R _{SINK}		V _{DD} = 13.5 V, V _{IN} = 0 V, I _O = 0.5 A	-	4.5	10	Ω	WB output resistance pulse width \leq 10 μ s			

Chara	cteristic	Symbol	Test Circuit	Condition	Min	Тур.	Max	Unit	Remarks
Under-	Detection	V _{DDUV}		_	5.0	5.5	6.0	v	Under voltage detection voltage and hysteresis (V _{DD} voltage detected)
voltage detection	Hysteresis	ΔV_{DDUV}		_	-	0.5	-	v	
	Turn-on delay time	^t d (ON)			-	0.25	1	\langle	
Switching times	Turn-on time	t _{ON}	1	V _{DD} = 13.5 V, V _{CPV} = 13.5 V,	-	0.5	2		UU, VU, WU, UB, VB and WB switching times
	Turn-off delay time	^t d (OFF)		$C_{OUT} = 12400 \text{ pF},$ $R_{G} = 47 \Omega$	-	0.25	₹//\	μs C	
	Turn-off time	tOFF			-	0.5	2		
Dead time	(Note 6)	t _{dead}	-	V_{DD} = 13.5 V, t_{dead} = t_{OFF} - $t_{d(ON)}$	-	0.25		μs	
Oscillating frequency		fosc	-	V _{DD} = 7 to 18V, R _{OSC} = 62 kΩ, C _{OSC} = 270 pF	80	100	120	kHz	
FAULT output voltage		VFAULT	-	V _{DD} = 7 to 18 V, I _{FAULT} = 1 mA)//	0.8	>	FAULT pin low-level voltage (open-drain)
FAULT output leakage current		IFAULT	-	V _{DD} = 7 to 18 V, V _{FAULT} = 18 V	(-	> -	10	μA	\mathcal{O}
FAULT out delay time	put	^t d(FAULT)	-	-		-	1	μs	

- Note3 : On-off output control, FAULT output and charge pump circuit operate from $V_{DD} \ge 4.5V$. However, charge pump voltage (CPV voltage) decreases by there are a lot of output currents in the condition with a low power supply voltage (V_{DD}). It may be not enough voltage (V_{GS}) to drive external power MOSFET. Be careful enough when using it .
- Note4 : When converting foward voltage of the charge pump circuit diode by 0.7V. Please use the diode of high-speed type (trr ≤ 100ns).
- Note5 : About the charge pump voltage

So as not to apply over-voltage to the gate-source voltage(V_{GS}) of external power MOSFET, and so as to become the best driving voltage, the clamping circuit is built into. When the CPV voltage reaches the value, so as not to apply over-voltage, the oscillation logic circuit of the charge pump is stopped.



Note6 : About the dead time

High-side/low-side arm shorting mode is disabled by the internal logic. All outputs can be turned off. The deadtime of this product is 1µs. That doesn't contain deadtime of external power MOSFET. Please set the deadtime of the input signal after considering the switching time of external power MOSFET.

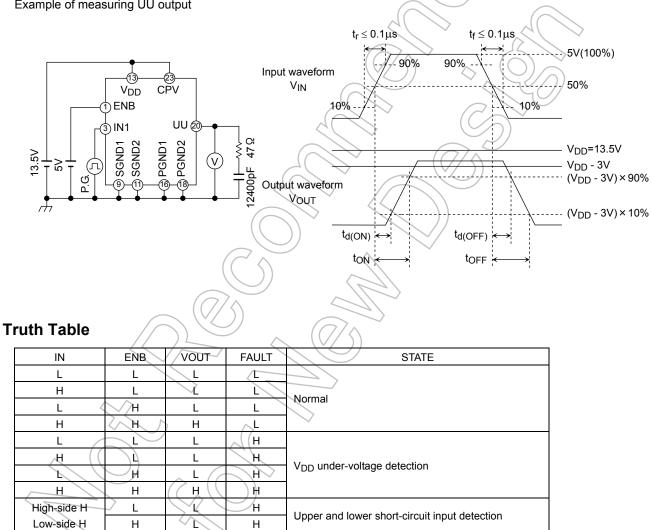
Note7 : About the direct input method of the charge pump oscillation frequency

By the oscillation signal from the outside to COSC it is possible to set up the charge pump oscillation. As this method, please input the signal to COSC after VDD becomes over 9V. (VCOSC < 5.5V) Moreover, please use the terminal ROSC by the resistance unconnection (open). When the CPV voltage reaches up to the clamping voltage, though the signal is input to COSC, the movement of the charge pump (oscillation) stops.

Test Circuit 1

Switching times

Example of measuring UU output

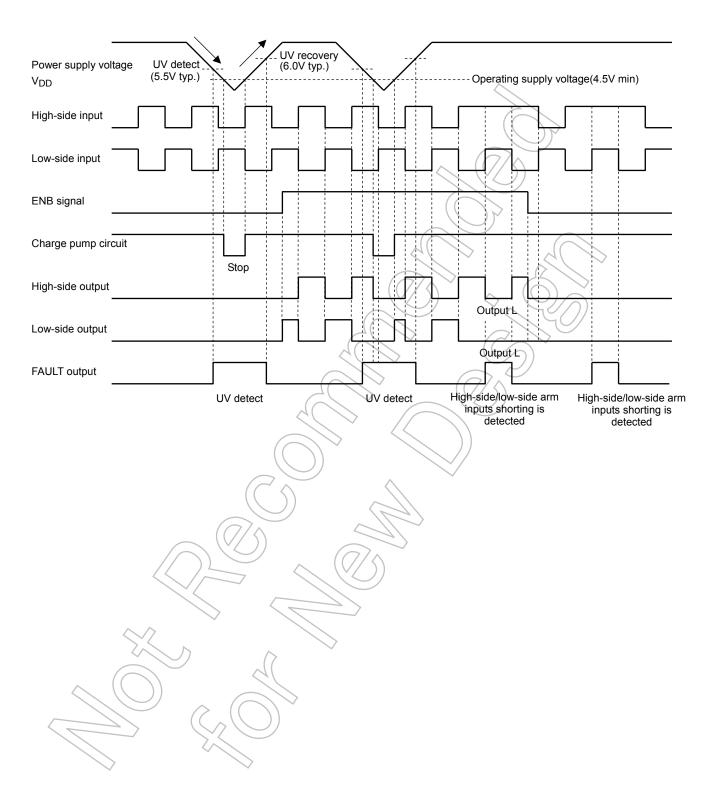


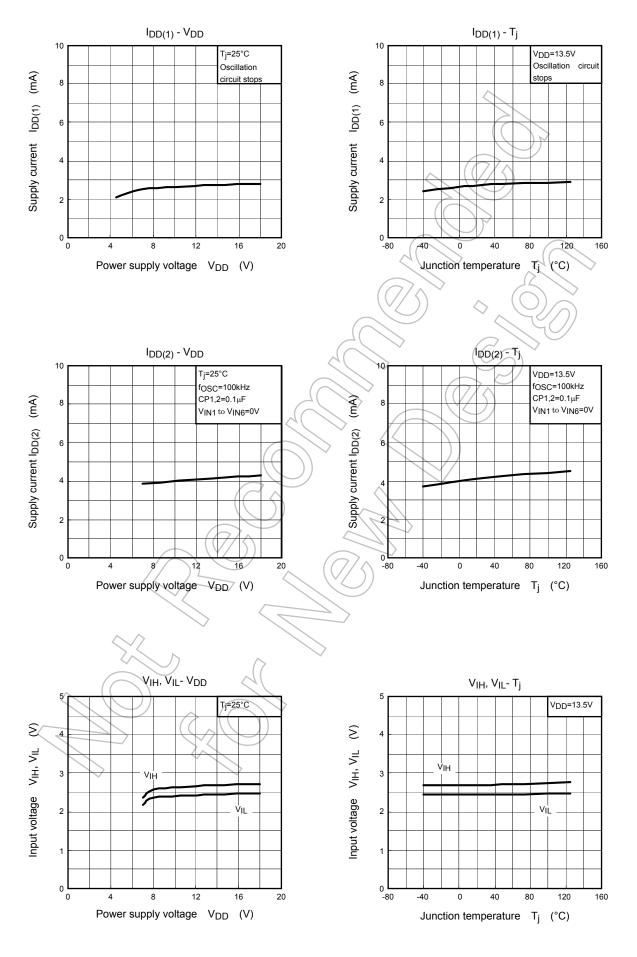
· When under-voltage (5.5V typ.) is detected, only FAULT outputs "H". Neither the output nor the operation of the charge pump circuit stops(off).

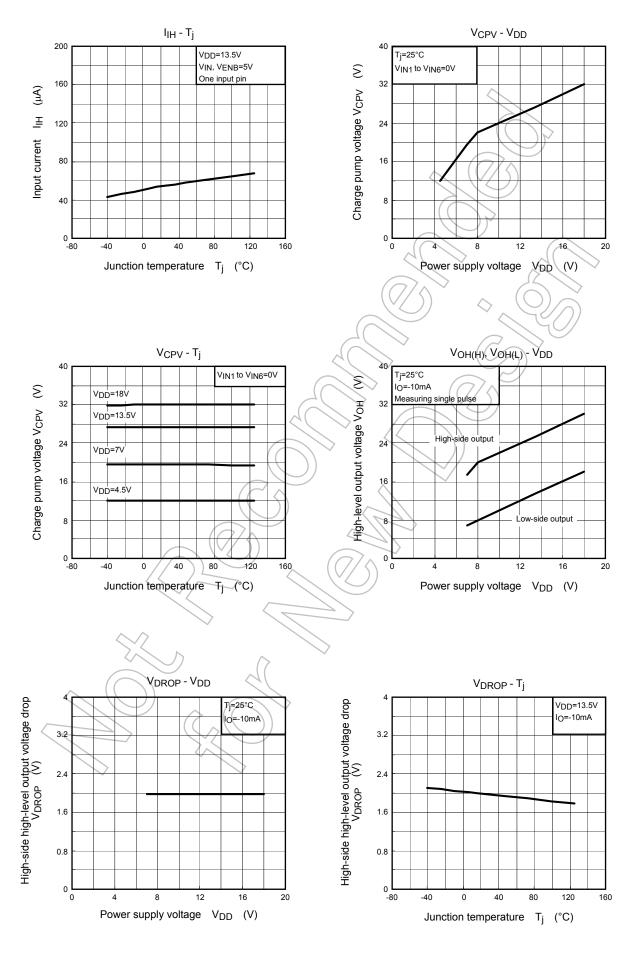
· When a in-phase high side and the low side input are the "H" levels, all the outputs be made "L" level, and the "H" level is output to FAULT.

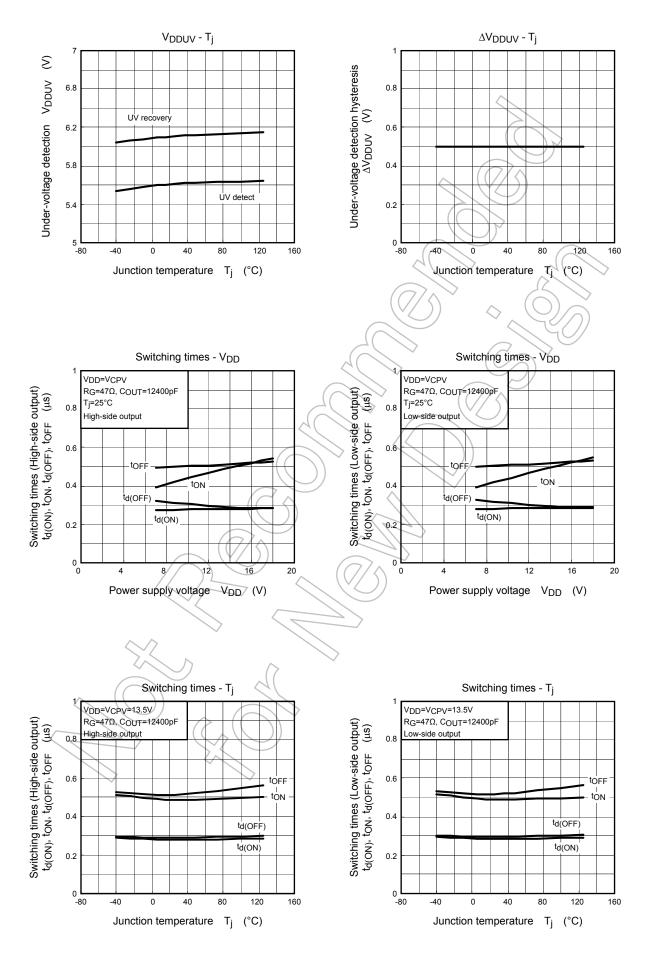
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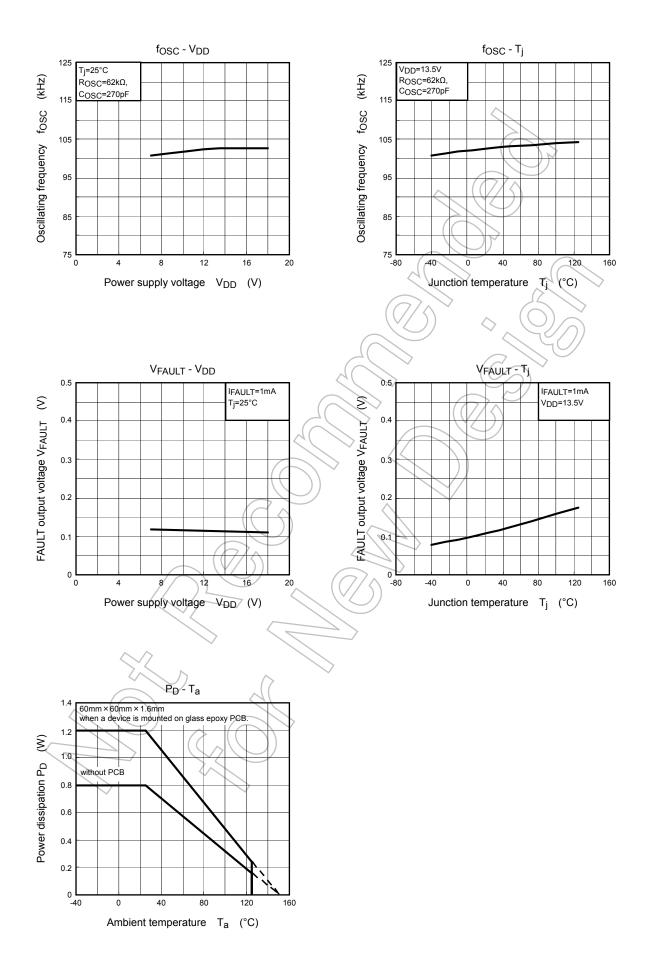
Timing chart









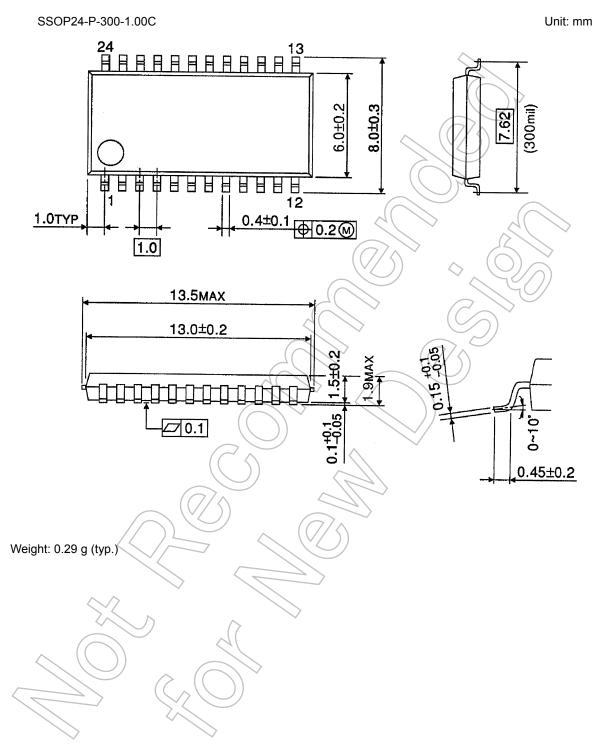


Usage Precautions

Precautions on dry packing

After unpacking dry or moisture-proof packing, make sure the device is mounted in place within 48 hours at a temperature and humidity of 30°C and 60% RH or less. Because the device is emboss-taped and cannot be processed by baking, always be sure to use it within the said allowable time after unpacking. Standard tape packing quantity: 2000 devices / reel (EL1).

Package Dimensions





RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.

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